

PM006N040AG



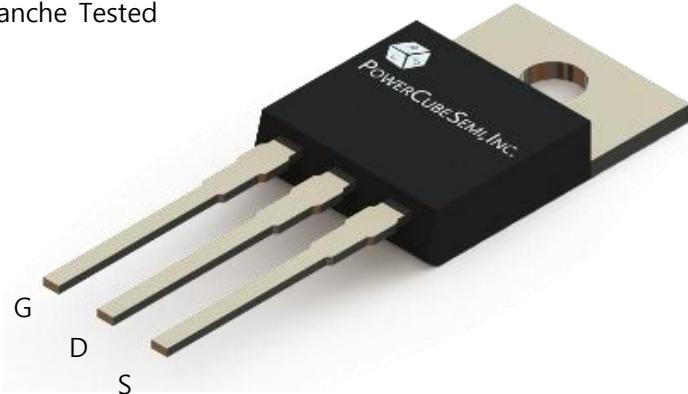
POWERCUBESEMI, INC.
Potential · Convergence · Smart

40V 100A 6.5mΩ Si Single N-ch Enhancement Mode Power MOSFET with Normal Diode

Features

Si Single N-ch Enhancement Mode Power MOSFET

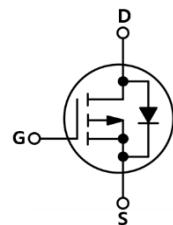
- Rated to 40V at 100Amps @ $T_J = 25^\circ\text{C}$
- Max $R_{DS(on)} = 6.5 \text{ m}\Omega$
- Typ $R_{DS(on)} = 5.2 \text{ m}\Omega$
- Gate Charge(Typ. $Q_g=50 \text{ nC}$)
- 100% Avalanche Tested



PKG type : TO-220

Application

- PWM
- Load Switching



Description

The PM006N040AG uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge. it can be used in a wide variety of applications.

Absolute Maximum Ratings

Symbol	Parameter	Test Condition	Value	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	40	V
I_D	Drain Current	$T_c=25^\circ\text{C}$	100	A
I_{DM}	Pulsed Drain Current	Pulse width limited by junction temperature	350	A
V_{GS}	Gate-Source Voltage		± 20	V
E_{AS}	Single Pulsed Avalanche Energy	$V_{DD}=20\text{V}, V_{GS}=10\text{V}, L=1.0\text{mH}, R_G=25\Omega$	670	mJ
P_d	Power Dissipation	$T_c=25^\circ\text{C}$	90	W
T_j	Operating Junction Temperature		150	$^\circ\text{C}$
T_{stg}	Storage Temperature		-55 to 150	$^\circ\text{C}$



Package Marking and Ordering Information

Device Marking	Device	Package	Packing Method	Tape width	Quantity
PM006N040AG	PM006N040	TO-220	TUBE	-	50

Electrical Characteristics of Si MOSFET

Symbol	Parameter	Test Condition	Numerical			Unit
			Min	Typ.	Max.	
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A, T_J = 25^\circ C$	40	45	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 40V, V_{GS} = 0V$	-	-	1	μA
I_{GSS}	Gate-Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	± 100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.2	1.5	1.9	V
$R_{DS(ON)}$	Static Drain-Source on state resistance	$V_{GS} = 10V, I_D = 20A$	-	5.2	6.5	$m\Omega$
g_{FS}	Forward Transconductance	$V_{DS} = 10V, I_D = 20A$	15	-	-	S
$t_{d(on)}$	Turn-on Delay time	$V_{DD} = 20 V, R_L = 1\Omega$ $V_{GS} = 10V, R_G = 3\Omega$	-	11	-	ns
T_r	Turn-on Rise time		-	10	-	
$t_{d(off)}$	Turn-off Delay time		-	38	-	
T_f	Turn-off Fall time		-	11	-	



Electrical Characteristics of Si MOSFET

Symbol	Parameter	Test Condition	Numerical		Unit
			Typ.	Max.	
$R_{\theta JC}$	Thermal Resistance, Junction to Case		1.67	-	°C/W
C_{iss}	Input Capacitance	$V_{DS} = 20V, V_{GS} = 0V, f = 1.0MHz$	4010	-	pF
C_{oss}	Output Capacitance		750	-	
C_{rss}	Reverse Transfer Capacitance		390	-	
$Q_{g(tot)}$	Total Gate Charge at 10V	$V_{DD} = 20V, I_D = 20A, V_{GS(on)} = 10V$	50	-	nC
Q_{gs}	Gate to Source Gate Charge		12	-	
Q_{gd}	Gate to Drain "Miller" Charge		13	-	

Electrical Characteristics of Si Diode

Symbol	Parameter	Test Condition	Numerical		Unit
			Typ.	Max.	
I_S	Maximum Continuous Drain to Source Diode Forward Current		-	80	A
V_{SD}	Drain to Source Diode Forward Voltage	$I_S = 10A, V_{GS} = 0V$	-	1.2	V
T_{rr}	Reverse Recovery Time	$I_F = 20A, V_{GS} = 0V, dI_F/dt = 100A/\mu s$	33	-	ns
Q_{rr}	Reverse Recovery Charge		34	-	nC

Typical Characteristics

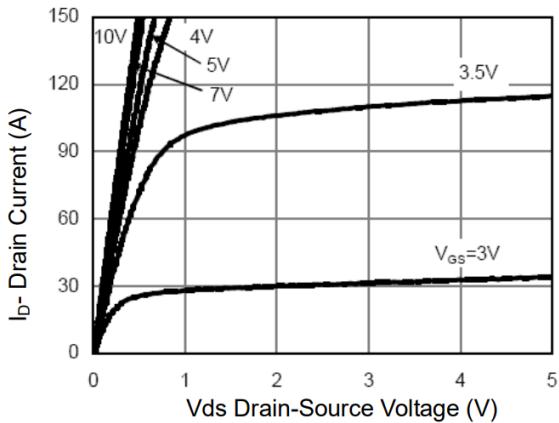


Figure 1. Output Characteristics

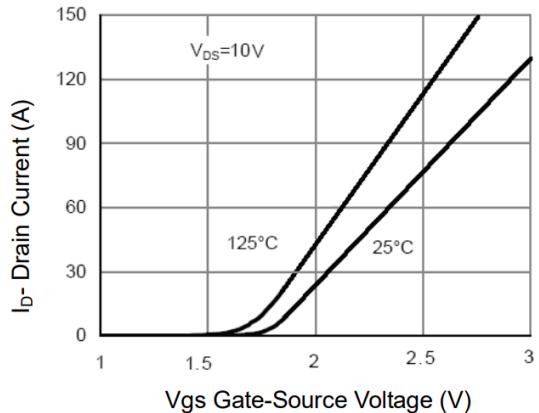


Figure 2. Transfer Characteristics

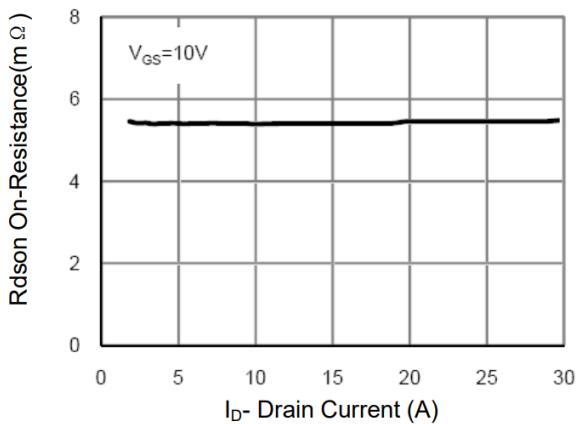


Figure 3. $R_{DS(ON)}$ vs. Drain Current

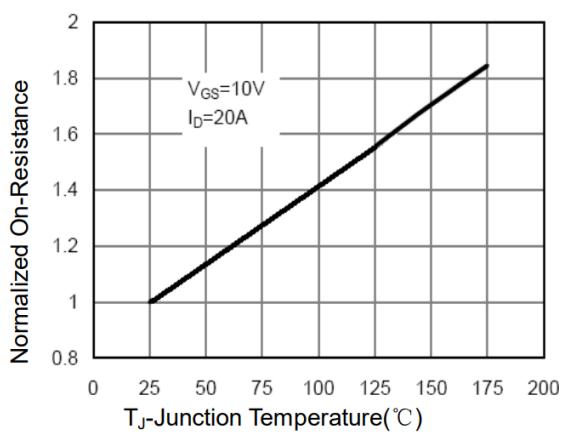


Figure 4. $R_{DS(ON)}$ vs. T_J

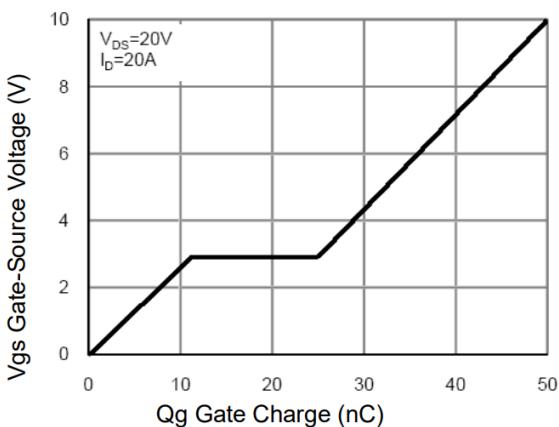


Figure 5. Gate Charge

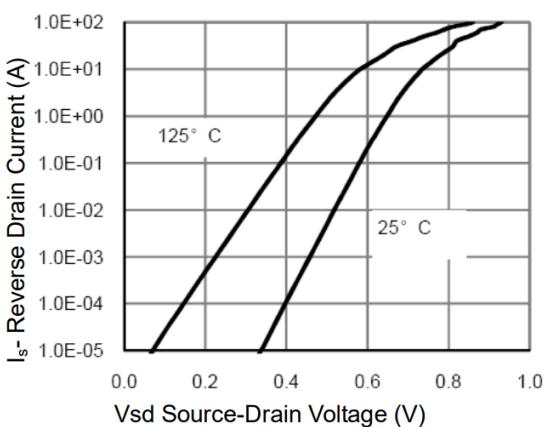


Figure 6. Source to Drain Diode Forward

Typical Characteristics

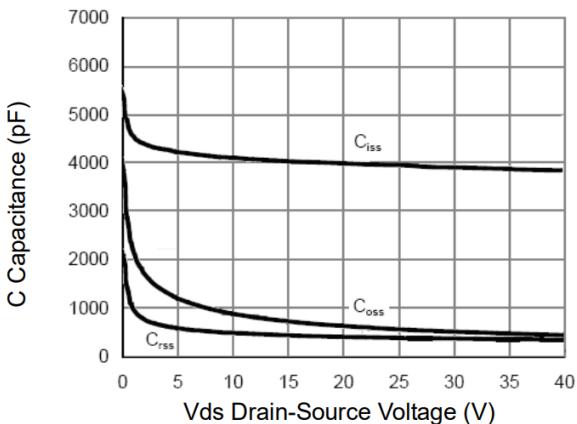


Figure 7. Capacitance characteristics

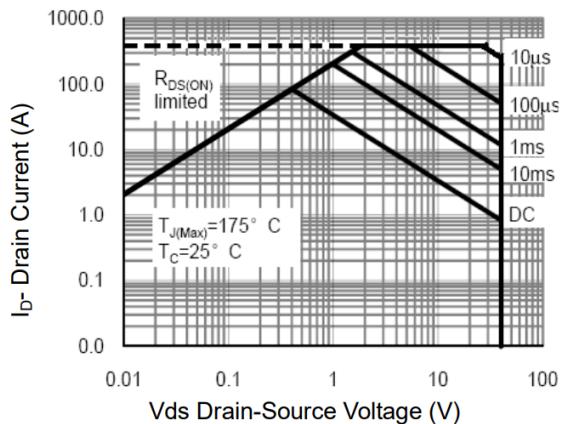


Figure 8. Safe Operation Area

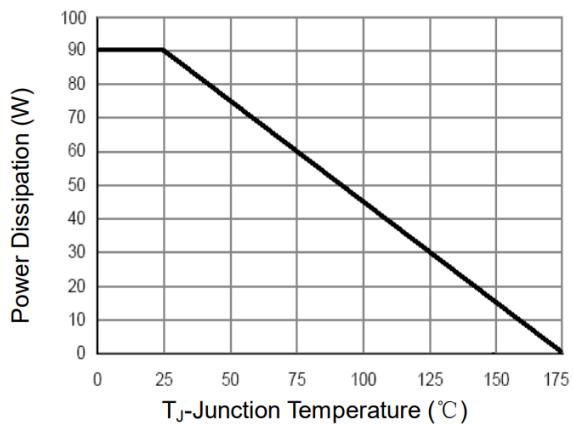


Figure 9. Power Derating

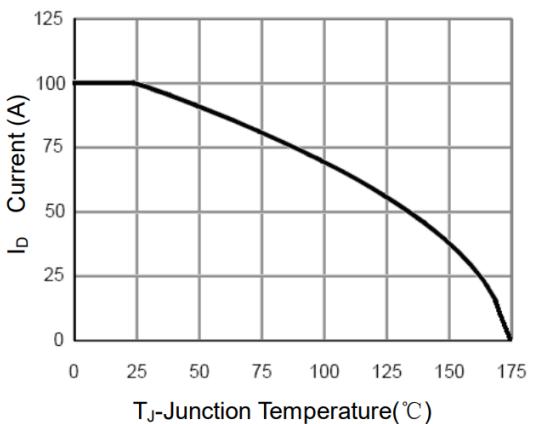


Figure 10. Drain Current vs. T_J

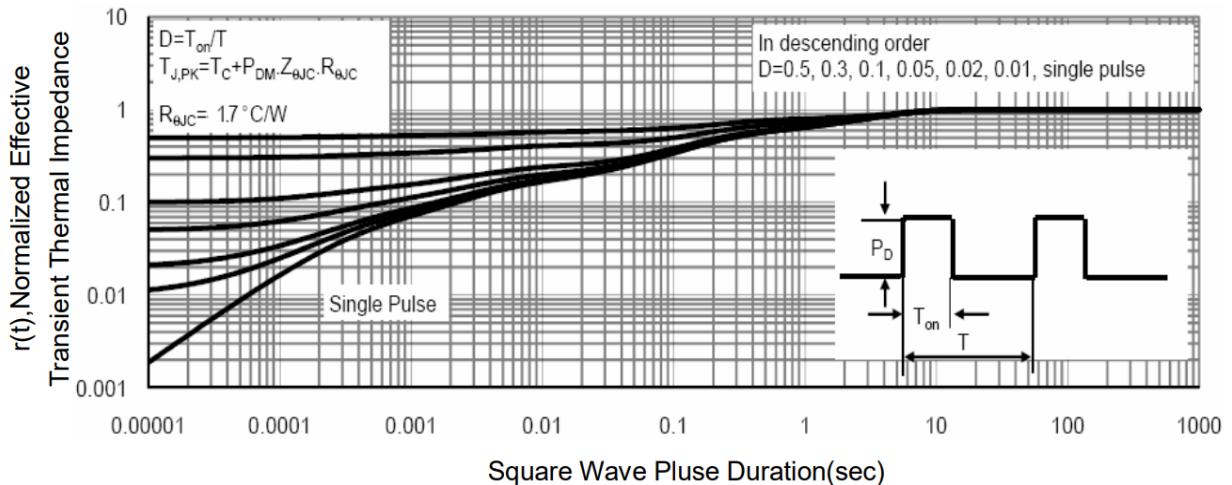


Figure 11. Normalized Maximum Transient Thermal Impedance



Package Outline

Unit : mm

